



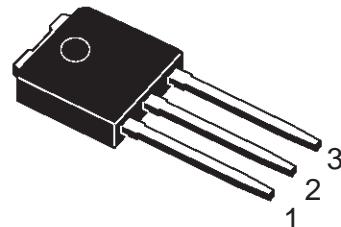
# STGD7NB120S-1

## N-CHANNEL 7A - 1200V - IPAK PowerMESH™ IGBT

PRELIMINARY DATA

TYPE	V <sub>CES</sub>	V <sub>CES(sat)</sub>	I <sub>C</sub>
STGD7NB120S-1	1200 V	< 2.1 V	7 A

- HIGH INPUT IMPEDANCE (VOLTAGE DRIVEN)
- VERY LOW ON-VOLTAGE DROP (V<sub>cesat</sub>)
- OFF LOSSES INCLUDE TAIL CURRENT
- HIGH CURRENT CAPABILITY

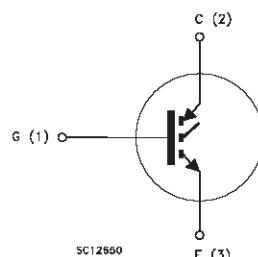


IPAK

### DESCRIPTION

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The suffix "S" identifies a family optimized achieve minimum on-voltage drop for low frequency applications (<1kHz).

### INTERNAL SCHEMATIC DIAGRAM



### APPLICATIONS

- MOTOR CONTROL
- LIGHT DIMMER
- INTRUSH CURRENT LIMITATION

### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CES</sub>	Collector-Emitter Voltage (V <sub>GS</sub> = 0)	1200	V
V <sub>EGR</sub>	Reverse Battery Protection	20	V
V <sub>GE</sub>	Gate-Emitter Voltage	+20	V
I <sub>C</sub>	Collector Current (continuos) at T <sub>C</sub> = 25°C	10	A
I <sub>C</sub>	Collector Current (continuos) at T <sub>C</sub> = 100°C	7	A
I <sub>CM</sub> (■)	Collector Current (pulsed)	20	A
P <sub>TOT</sub>	Total Dissipation at T <sub>C</sub> = 25°C	55	W
	Derating Factor	0.4	W/°C
T <sub>stg</sub>	Storage Temperature	-65 to 150	°C
T <sub>j</sub>	Max. Operating Junction Temperature	150	°C

(■) Pulse width limited by safe operating area

## STGD7NB120S-1

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### THERMAL DATA

Rthj-case	Thermal Resistance Junction-case Max	2.27	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	100	°C/W
Rthc-h	Thermal Resistance Case-heatsink Typ	0.5	°C/W

### ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>BR</sub> (CES)	Collectro-Emitter Breakdown Voltage	I <sub>C</sub> = 250 µA, V <sub>GE</sub> = 0	1200			V
V <sub>BR</sub> (ECR)	Emitter-Collectro Breakdown Voltage	I <sub>C</sub> = 10mA, V <sub>GE</sub> = 0	20			V
I <sub>CES</sub>	Collector cut-off (V <sub>GE</sub> = 0)	V <sub>CE</sub> = Max Rating, T <sub>C</sub> = 25 °C V <sub>CE</sub> = Max Rating, T <sub>C</sub> = 125 °C		50 250	µA µA	
I <sub>GES</sub>	Gate-Emitter Leakage Current (V <sub>CE</sub> = 0)	V <sub>GE</sub> = ±20V, V <sub>CE</sub> = 0			±100	nA

### ON (1)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>GE(th)</sub>	Gate Threshold Voltage	V <sub>CE</sub> = V <sub>GE</sub> , I <sub>C</sub> = 250µA	3		5	V
V <sub>GE</sub>	Gate Emitter Voltage	V <sub>CE</sub> =2.5V, I <sub>C</sub> = 2A, T <sub>j</sub> = 25÷125°C			6.5	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 3.5 A V <sub>GE</sub> = 15V, I <sub>C</sub> = 7 A V <sub>GE</sub> = 15V, I <sub>C</sub> = 10 A			1.6 2.1	V V

### DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g <sub>fs</sub>	Forward Transconductance	V <sub>CE</sub> = 25 V , I <sub>C</sub> =7 A	2.5	4.5		S
C <sub>ies</sub>	Input Capacitance			430		pF
C <sub>oes</sub>	Output Capacitance	V <sub>CE</sub> = 25V, f = 1 MHz, V <sub>GE</sub> = 0		40		pF
C <sub>res</sub>	Reverse Transfer Capacitance			7		pF
Q <sub>g</sub>	Gate Charge	V <sub>CE</sub> = 960V, I <sub>C</sub> = 7 A, V <sub>GE</sub> = 15V		29		nC
I <sub>CL</sub>	Latching Current	V <sub>clamp</sub> = 960V , T <sub>j</sub> = 150°C R <sub>G</sub> = 1KΩ	10			A

### SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>CC</sub> = 960 V, I <sub>C</sub> = 7 A		570		ns
t <sub>r</sub>	Rise Time	R <sub>G</sub> = 1KΩ , V <sub>GE</sub> = 15 V		270		ns
(di/dt) <sub>on</sub>	Turn-on Current Slope	V <sub>CC</sub> = 960 V, I <sub>C</sub> = 7 A, R <sub>G</sub> =1KΩ V <sub>GE</sub> = 15 V, T <sub>j</sub> = 125°C		800		A/µs
E <sub>on</sub>	Turn-on Switching Losses			3.2		µJ

**ELECTRICAL CHARACTERISTICS (CONTINUED)****SWITCHING OFF**

<b>Symbol</b>	<b>Parameter</b>	<b>Test Conditions</b>	<b>Min.</b>	<b>Typ.</b>	<b>Max.</b>	<b>Unit</b>
$t_c$	Cross-over Time			4.9		$\mu s$
$t_r(V_{off})$	Off Voltage Rise Time	$V_{cc} = 960 \text{ V}$ , $I_C = 7 \text{ A}$ , $R_{GE} = 1\text{K}\Omega$ , $V_{GE} = 15 \text{ V}$		2.9		$\mu s$
$t_f$	Fall Time			3.3		$\mu s$
$E_{off}(**)$	Turn-off Switching Loss			15		mJ
$t_c$	Cross-over Time			7.5		$\mu s$
$t_r(V_{off})$	Off Voltage Rise Time	$V_{cc} = 960 \text{ V}$ , $I_C = 7 \text{ A}$ , $R_{GE} = 1\text{K}\Omega$ , $V_{GE} = 15 \text{ V}$		5.5		$\mu s$
$t_f$	Fall Time	$T_j = 125 \text{ }^{\circ}\text{C}$		6.2		$\mu s$
$E_{off}(**)$	Turn-off Switching Loss			22		mJ

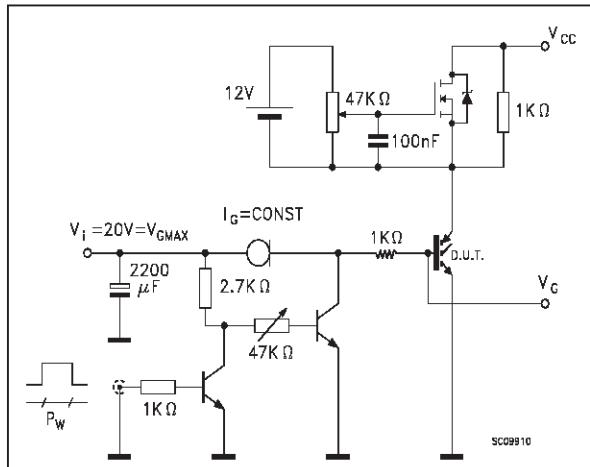
Note: 1. Pulsed: Pulse duration = 300  $\mu s$ , duty cycle 1.5 %.

2. Pulse width limited by max. junction temperature.

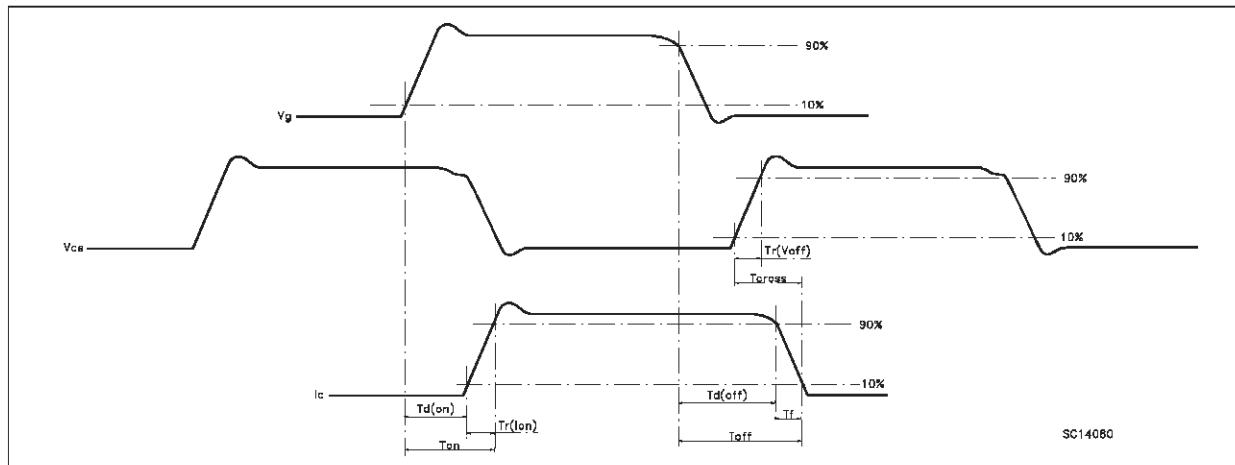
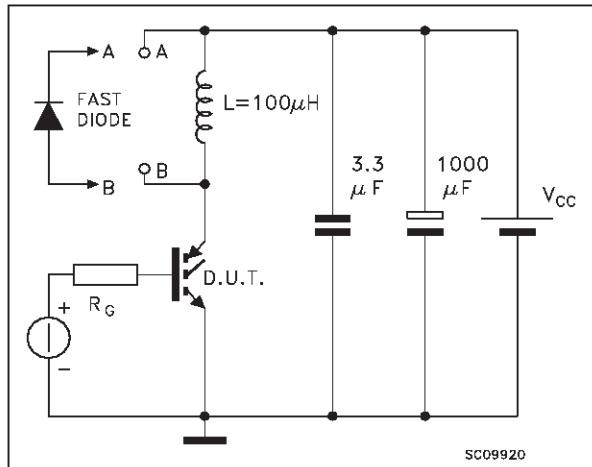
(\*\*)Losses include Also the Tail (Jedec Standardization)

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**Fig. 1: Gate Charge test Circuit**

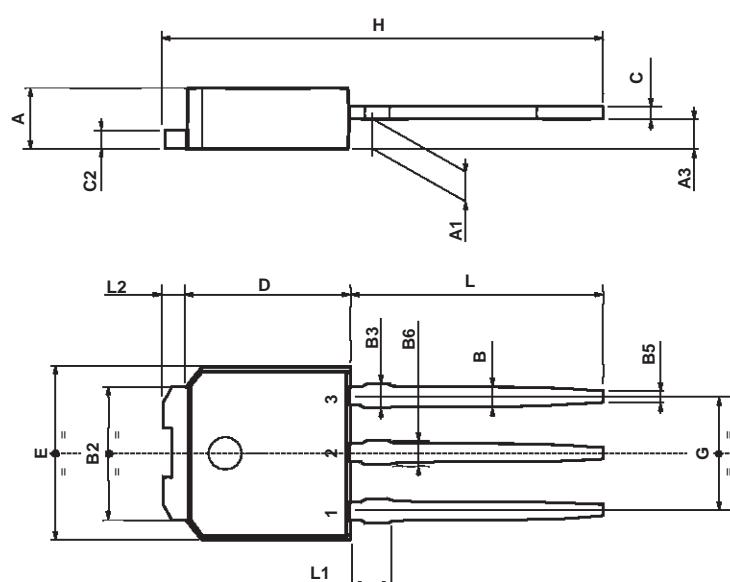


**Fig. 2: Test Circuit For Inductive Load Switching**



## TO-251 (IPAK) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
B	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
C	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
H	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



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